

# FUNDAMENTALS OF ADJOINT SENSITIVITIES IN ELECTROMAGNETICS

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## Outline

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**Introduction: Challenges of simulation-based optimization**

**Background: AVM & self-adjoint sensitivities of S-parameters**

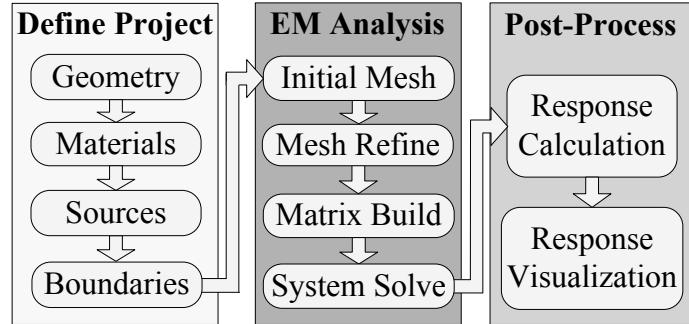
**Point of Interest: Accuracy of an FDFD implementation**

**Applications: Response gradients in design tuning**

**Applications: Response gradients in imaging**

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## Introduction: Simulation as Forward Model



$F_x : p \rightarrow x$  maps parameters  $p$  into field solution  $x$

$F_r : p \rightarrow r$  maps parameters  $p$  into responses  $r$

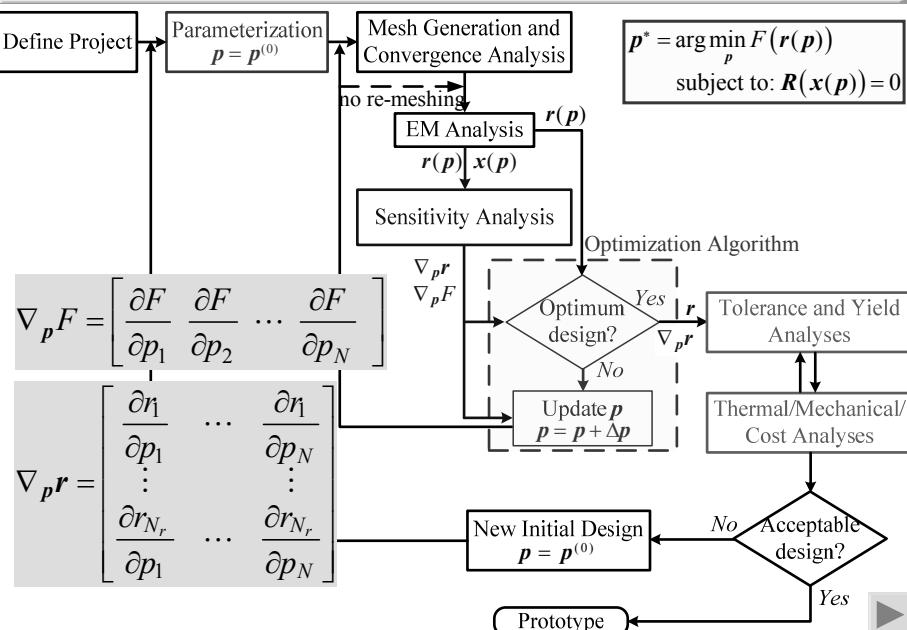
$p$  shape and material parameters

$x(p)$  field solution

$r(x(p))$  responses

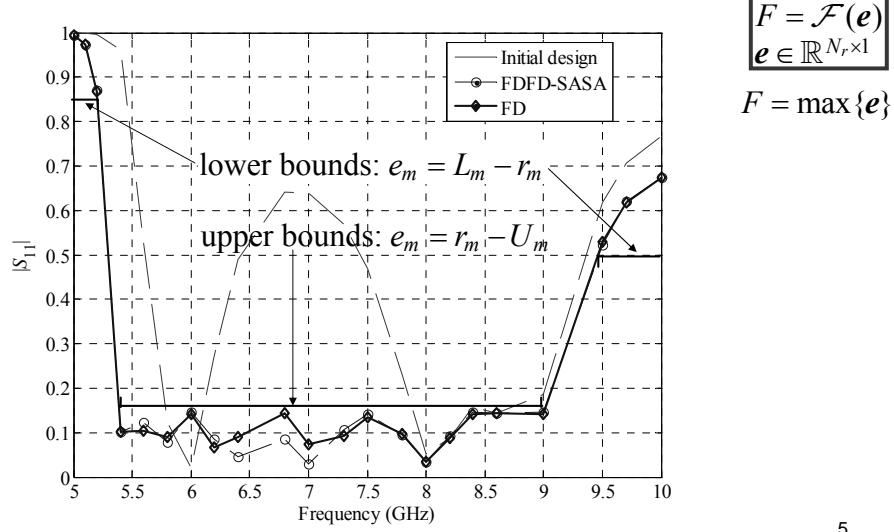
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## Introduction: Simulation-Based Optimization (Design Flowchart)



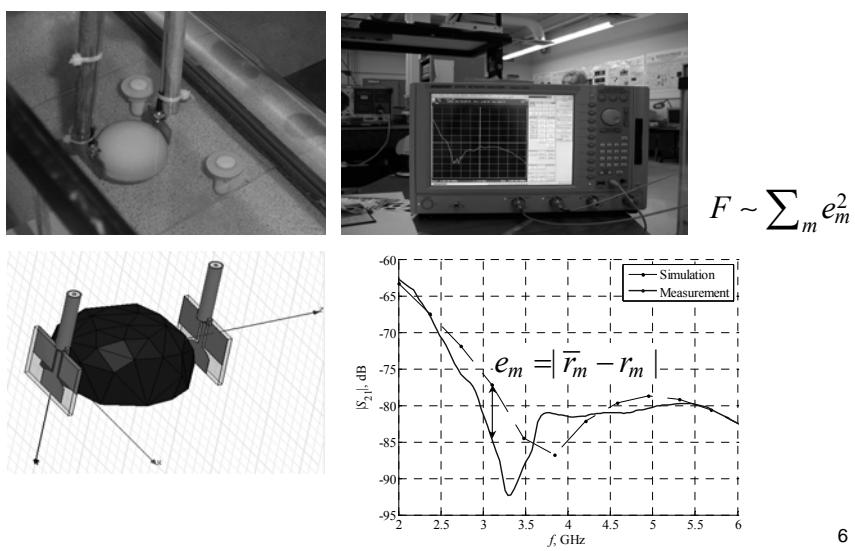
## Introduction: Simulation-Based Optimization, cont.

example objective function  $F - \text{minimax}$  formulation



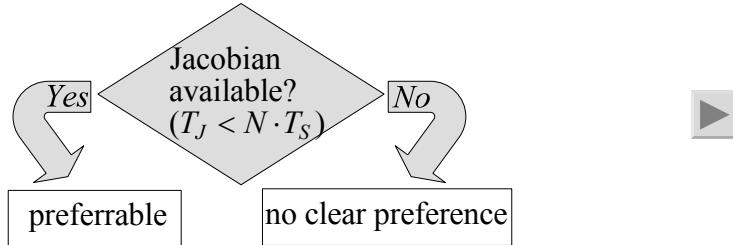
## Introduction: Simulation-Based Optimization, cont.

example objective function  $F - \ell_2$  formulation in imaging



## Introduction: Pros & Cons of Gradient-based Optimization

- fast convergence, i.e., number of iterations is relatively small  
*overall speed conditional upon Jacobian availability*



- solution is only local (starting point is important)
- convergence to a good solution is not guaranteed

gradient-based algorithms preferred in tuning tasks

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## Challenges in Optimization with Numerical Simulations

- $F$  is a strongly nonlinear non-analytical function of  $p$
- optimization problem is not convex
- evaluation of  $F$  is computationally expensive
- numerical errors are unavoidable – accuracy is limited by resources
- Jacobian is not available
- response-level Jacobian estimates are unreliable and time-consuming
- interfacing external optimization algorithms with commercial EM solvers is fraught with technical complications

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## Dos and Don'ts in Optimization with Simulators

- ⇒ determine the accuracy of the simulated responses  $\delta$ 
  - perform mesh convergence analysis  $\delta^{(n)} = \| \mathbf{r}^{(n+1)} - \mathbf{r}^{(n)} \| \leq \delta$
  - typical  $\delta$  is about 0.01 for S-parameters of passive devices
- ⇒ select the values of the termination criteria accordingly
  - objective function: stop if  $\Delta F^{(n)} \leq \delta_F$   $\Delta F^{(n)} = |F^{(n)} - F^{(n-1)}|$
  - $\delta_F \approx |\mathcal{F}(\delta \mathbf{u})|$   $F^{(n)} = \mathcal{F}(\mathbf{e}^{(n)})$
  - step in shape-parameter space: stop if  $\|\Delta \mathbf{p}^{(n)}\| \leq \delta_p$
  - $\delta_p \approx 0.75l_{\min}$  
  - observe termination criteria for 2 or 3 consecutive iterations
- ⇒ do not change mesh topology from one optimization iteration to another

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## Sensitivity Analysis Based on EM Simulations

### objective

$$\nabla_p \mathbf{r} \text{ subject to } \mathbf{R}(\mathbf{x}, \mathbf{p}) = \mathbf{0} \quad \llcorner$$

Jacobian must be obtained within  $T_J \ll NT_S$  

$$\frac{dr}{dp_n} \approx \frac{r(\mathbf{p} + \Delta p_n \mathbf{u}_n) - r(\mathbf{p})}{\Delta p_n}, \quad n = 1, \dots, N$$

response-level finite differences

### approach – adjoint variable method

overhead is at the most one additional EM simulation regardless of  $N$

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## Adjoint Variable Method in Electromagnetics

derivatives with respect to parameter  $p_n, n = 1, \dots, N$

### system equations

$$\mathbb{L}\mathbf{E} = \mathbf{g}, \quad R(\mathbf{E}) = \mathbb{L}\mathbf{E} - \mathbf{g} = 0$$



$$\frac{\partial \mathbb{L}}{\partial p_n} \mathbf{E} + \mathbb{L} \frac{\partial \mathbf{E}}{\partial p_n} = \frac{\partial \mathbf{g}}{\partial p_n}$$



$$\left\langle \hat{\mathbf{E}}, \frac{\partial R}{\partial p_n} \mathbf{E} \right\rangle = - \left\langle \hat{\mathbf{E}}, \mathbb{L} \frac{\partial \mathbf{E}}{\partial p_n} \right\rangle$$

$$\frac{\partial R}{\partial p_n} = \frac{\partial \mathbb{L}}{\partial p_n} \bar{\mathbf{E}} - \frac{\partial \mathbf{g}}{\partial p_n}$$

### response

$$F(\mathbf{E}) = \iiint_{\Omega} f(\mathbf{E}) d\Omega$$



$$\frac{\partial F}{\partial p_n} - \frac{\partial^e F}{\partial p_n} = \iiint_{\Omega} \left( \sum_{\xi=x,y,z} \frac{\partial f}{\partial E_{\xi}} \cdot \frac{\partial E_{\xi}}{\partial p_n} \right) d\Omega$$



$$\frac{\partial F}{\partial p_n} - \frac{\partial^e F}{\partial p_n} = \left\langle \frac{\partial \mathbf{E}}{\partial p_n}, \hat{\mathbf{g}} \right\rangle$$

$$\hat{\mathbf{g}} = \sum_{\xi=x,y,z} \frac{\partial f}{\partial E_{\xi}} \hat{\mathbf{a}}_{\xi}$$



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## AVM in Electromagnetics, cont.

the “transpose” (or pseudo-adjoint) of the EM operator is the one where the constitutive tensors are  $\boldsymbol{\epsilon}^T$  and  $\boldsymbol{\mu}^T$

$$\langle \mathbf{f}, \mathbb{L}\mathbf{g} \rangle = \langle \mathbf{g}, \mathbb{L}^T \mathbf{f} \rangle$$

### system equations

$\vdots$

$$\left\langle \hat{\mathbf{E}}, \frac{\partial R}{\partial p_n} \mathbf{E} \right\rangle = - \left\langle \hat{\mathbf{E}}, \mathbb{L} \frac{\partial \mathbf{E}}{\partial p_n} \right\rangle$$



$$\left\langle \hat{\mathbf{E}}, \frac{\partial R}{\partial p_n} \mathbf{E} \right\rangle = - \left\langle \frac{\partial \mathbf{E}}{\partial p_n}, \mathbb{L}^T \hat{\mathbf{E}} \right\rangle \hat{\mathbf{g}}$$

### response

$\vdots$

$$\frac{\partial F}{\partial p_n} - \frac{\partial^e F}{\partial p_n} = \left\langle \frac{\partial \mathbf{E}}{\partial p_n}, \hat{\mathbf{g}} \right\rangle$$



$$\frac{\partial F}{\partial p_n} = \frac{\partial^e F}{\partial p_n} - \iiint_{\Omega} \hat{\mathbf{E}} \cdot \frac{\partial R(\bar{\mathbf{E}})}{\partial p_n} d\Omega$$

$$\mathbb{L}^T \hat{\mathbf{E}} = \hat{\mathbf{g}}$$



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## AVM in Electromagnetics: Implementation with FDFD

$$\frac{\partial F}{\partial p_n} = \frac{\partial^e F}{\partial p_n} - \iiint_{\Omega} \hat{\mathbf{E}} \cdot \frac{\partial R(\bar{\mathbf{E}})}{\partial p_n} d\Omega \quad \mathbb{L}^T \hat{\mathbf{E}} = \hat{\mathbf{g}}$$

$$\mathbb{L}\mathbf{E} = \mathbf{g}, \quad R(\mathbf{E}) = \mathbb{L}\mathbf{E} - \mathbf{g} = 0$$

assume residual  $R$  uses a FDFD model based on Helmholtz equation

$$R(\mathbf{E}) = \nabla \times \tilde{\boldsymbol{\mu}}_r^{-1} \nabla \times \mathbf{E} - k_0^2 \tilde{\boldsymbol{\epsilon}}_r \mathbf{E} + j\omega\mu_0 \mathbf{J} = 0$$

after FD discretization

*source term*

$$\begin{aligned} &\Leftrightarrow C^2 \mathbf{E} + \alpha \mathbf{E} - \mathbf{G} = 0 \\ &C^2 \approx -\nabla \times \boldsymbol{\mu}_r^{-1} \nabla \times \\ &\alpha = k_0^2 [\epsilon_r - j\epsilon_r \tan \delta_d - j\sigma(\omega\epsilon_0)^{-1}] \\ &\mathbf{G} = j\omega\mu_0 \mathbf{J} \end{aligned}$$

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## AVM in Electromagnetics: Implementation with FDFD, cont.

the double-curl operator is discretized using central-node FD grid

$$C^2 \approx -\nabla \times \boldsymbol{\mu}_r^{-1} \nabla \times$$

*x*-component

$$(C^2 \mathbf{E})_x = \frac{D_{yy}^\mu E_x}{\Delta y^2} + \frac{D_{zz}^\mu E_x}{\Delta z^2} - \frac{D_{yx}^\mu E_y}{\Delta y \Delta x} - \frac{D_{zx}^\mu E_z}{\Delta z \Delta x}$$

$$(D_{yy}^\mu E_x)_{(x_0, y_0, z_0)} = \frac{E_{x(x_0, y_0 + \Delta y, z_0)}}{\tilde{\mu}_{r(x_0, y_0 + \Delta y/2, z_0)}} + \frac{E_{x(x_0, y_0 - \Delta y, z_0)}}{\tilde{\mu}_{r(x_0, y_0 - \Delta y/2, z_0)}} - \left[ \frac{1}{\tilde{\mu}_{r(x_0, y_0 + \Delta y/2, z_0)}} + \frac{1}{\tilde{\mu}_{r(x_0, y_0 - \Delta y/2, z_0)}} \right] \cdot E_{x(x_0, y_0, z_0)}$$

$$(D_{yx}^\mu E_y)_{(x_0, y_0, z_0)} = \frac{1}{4} \left[ \frac{E_{y(x_0 + \Delta x, y_0 + \Delta y, z_0)} - E_{y(x_0 - \Delta x, y_0 + \Delta y, z_0)}}{\tilde{\mu}_{r(x_0, y_0 + \Delta y, z_0)}} - \frac{E_{y(x_0 + \Delta x, y_0 - \Delta y, z_0)} - E_{y(x_0 - \Delta x, y_0 - \Delta y, z_0)}}{\tilde{\mu}_{r(x_0, y_0 - \Delta y, z_0)}} \right]. \quad 14$$

## AVM in Electromagnetics: Implementation with FDFD, cont.

linear operator and source term  $\mathbb{L} = C^2 + \alpha, \mathbf{g} = \mathbf{G}$

residual derivative

$$\frac{\partial R(\bar{\mathbf{E}})}{\partial p_n} = \frac{\partial \mathbb{L}}{\partial p_n} \bar{\mathbf{E}} - \frac{\partial \mathbf{g}}{\partial p_n}$$

$$\frac{\partial R(\bar{\mathbf{E}})}{\partial p_n} = \frac{\partial C^2 \bar{\mathbf{E}}}{\partial p_n} + \frac{\partial \alpha}{\partial p_n} \bar{\mathbf{E}} - \frac{\partial \mathbf{G}}{\partial p_n} \quad \text{usually zero}$$

derivatives of system coefficients wrt material parameters

$$\frac{\partial C^2 \bar{\mathbf{E}}}{\partial \tilde{\mu}_r} = \begin{cases} -\frac{C^2 \bar{\mathbf{E}}}{\tilde{\mu}_r}, & \text{if } p_n = \mu_r \\ 0, & \text{if } p_n = \sigma \text{ or } \tan \delta_d \end{cases} \quad \frac{\partial \alpha}{\partial p_n} = \begin{cases} k_0^2(1 - j \tan \delta_d), & \text{if } p_n = \epsilon_r \\ -j \frac{k_0^2}{\omega \epsilon_0}, & \text{if } p_n = \sigma \\ -j \epsilon_r k_0^2, & \text{if } p_n = \tan \delta_d \end{cases}$$

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## AVM in Electromagnetics: Implementation with FDFD, cont.

summary of exact sensitivity analysis with the FDFD method

$$\frac{\partial F}{\partial p_n} = \frac{\partial^e F}{\partial p_n} - \iiint_{\Omega} \hat{\mathbf{E}} \cdot \frac{\partial R(\bar{\mathbf{E}})}{\partial p_n} d\Omega$$

where

$$\frac{\partial R(\bar{\mathbf{E}})}{\partial p_n} = \frac{\partial C^2 \bar{\mathbf{E}}}{\partial p_n} + \frac{\partial \alpha}{\partial p_n} \bar{\mathbf{E}}$$

and the adjoint field is the solution of

$$\mathbb{L}^T \hat{\mathbf{E}} = \hat{\mathbf{g}}, \quad \hat{\mathbf{g}} = \sum_{\xi=x,y,z} \frac{\partial f}{\partial E_\xi} \hat{\mathbf{a}}_\xi$$

this formula is directly applicable with material parameters

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### AVM in Electromagnetics: Implementation with FDFD, cont.

[Nikolova, Zhu, Song, Hasib, and Bakr, *IEEE Trans. Microwave Theory Tech.*, June 2009]

approximate sensitivity analysis for shape parameters (FDFD method)

$$\frac{\partial F}{\partial p_n} \approx \frac{\partial^e F}{\partial p_n} - \iiint_{\Omega} \hat{\mathbf{E}}_n \cdot \frac{\Delta R(\bar{\mathbf{E}})}{\Delta p_n} d\Omega$$

where

$$\frac{\Delta R(\bar{\mathbf{E}})}{\Delta p_n} = \frac{\Delta C^2 \bar{\mathbf{E}}}{\Delta p_n} + \frac{\Delta \alpha}{\Delta p_n} \cdot \bar{\mathbf{E}} - \frac{\Delta(j\omega\mu_0 \mathbf{J}^{\text{ind}})}{\Delta p_n}$$

and the adjoint field is the solution of the perturbed adjoint problem

$$\mathbb{L}_n^T \hat{\mathbf{E}}_n = \hat{\mathbf{g}}, \quad \hat{\mathbf{g}} = \sum_{\xi=x,y,z} \frac{\partial f}{\partial E_\xi} \hat{\mathbf{a}}_\xi$$

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### AVM in Electromagnetics: Implementation with MoM

[Georgieva, Glavic, Bakr, and Bandler, *IEEE Trans. Microwave Theory Tech.*, Dec. 2002]

the linear EM problem in matrix form

$$\mathbf{ZI} = \mathbf{V} \iff \mathbb{L}\mathbf{x} = \mathbf{g} \text{ or } \mathbf{R}(\mathbf{x}) = \mathbb{L}\mathbf{x} - \mathbf{g} = 0$$

$$\Rightarrow \mathbb{L} = \mathbf{Z} \text{ and } \mathbf{g} = \mathbf{V} \Rightarrow \mathbf{R}(\bar{\mathbf{I}}) = \mathbf{Z}\bar{\mathbf{I}} - \mathbf{V}$$

$\mathbf{Z}(p)$

system matrix

$\mathbf{I} = [i_1 \dots i_M]^T$

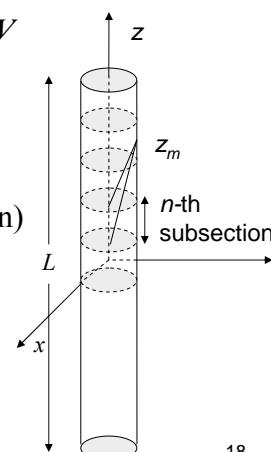
state variable vector (solution)

$\mathbf{V} = [v_1 \dots v_M]^T$

excitation vector

$\mathbf{p} = [p_1 \dots p_N]^T$

design variables



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## AVM in Electromagnetics: Implementation with MoM

exact sensitivity formula for linear deterministic problems in matrix form

$$\frac{\partial F}{\partial p_n} = \frac{\partial^e F}{\partial p_n} - \left\langle \hat{\mathbf{I}}, \frac{\partial R(\bar{\mathbf{I}})}{\partial p_n} \right\rangle \quad \frac{\partial R(\bar{\mathbf{I}})}{\partial p_n} = \frac{\partial \mathbf{Z}}{\partial p_n} \bar{\mathbf{I}} - \frac{\partial \mathbf{V}}{\partial p_n}$$

$\frac{\partial F}{\partial p_n} = \frac{\partial^e F}{\partial p_n} + \hat{\mathbf{I}}^T \cdot \left( \frac{\partial \mathbf{V}}{\partial p_n} - \frac{\partial \mathbf{Z}}{\partial p_n} \bar{\mathbf{I}} \right), \quad n = 1, \dots, N$

*usually zero*

where

$$\mathbf{Z}^T \hat{\mathbf{I}} = [\nabla_I F]_{I=\bar{I}}^T$$

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## S-parameter Self-adjoint Sensitivity Analysis

[Nikolova, Zhu, Song, Hasib, and Bakr, *IEEE Trans. Microwave Theory Tech.*, June 2009]

S-parameters as functionals of the  $\mathbf{E}$ -field at the ports

$$S_{kj}^{(\nu)} = \frac{\iint_{S_k} (\mathbf{E}_j \times \mathbf{h}_k^{(\nu)}) \cdot d\mathbf{s}}{\iint_{S_j} (\mathbf{E}_j^{\text{inc}} \times \mathbf{h}_j^{(\nu)}) \cdot d\mathbf{s}} - \delta_{kj}, \quad \delta_{kj} = \begin{cases} 1, & k = j \\ 0, & k \neq j \end{cases} \quad S_{kj}^{(\nu)} = \frac{F_{kj}}{V_j} - \delta_{kj}$$

$k, j = 1, \dots, K$

assume ports do not depend on  $p$

modal vectors and magnitudes  
are then independent of  $p$

modal vectors

$$\iint_{S_\zeta} (\mathbf{e}_\zeta^{(\nu)} \times \mathbf{h}_\zeta^{(\nu)}) \cdot d\mathbf{s} = \begin{cases} 1, & \text{if } \nu = \nu' \\ 0, & \text{if } \nu \neq \nu' \end{cases}$$

modal incident-wave magnitude

$$V_j = \iint_{S_j} (\mathbf{E}_j^{\text{inc}} \times \mathbf{h}_j^{(\nu)}) \cdot d\mathbf{s}$$

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### **S-parameter Self-adjoint Sensitivity Analysis, cont.**

the generalized response

$$F(\mathbf{E}) = \iiint_{\Omega} f(\mathbf{E}) d\Omega + \iint_{S_{\Omega}} f_s(\mathbf{E}) ds$$

in the case of S-parameters,  $F = F_{kj}$     $F_{kj} = \iint_{S_k} (\mathbf{E}_j \times \mathbf{h}_k^{(v)}) \cdot d\mathbf{s}$

$$f = 0 \text{ and } f_s = \begin{cases} (\mathbf{E}_j \times \mathbf{h}_k^{(v)}) \cdot \mathbf{a}_n, & \text{at } S_k \\ 0, & \text{elsewhere on } S_{\Omega} \end{cases}$$

excitation via port boundary (no volume sources!)

$$\mathbb{L}\mathbf{E} = 0 \quad \mathbb{L}^T \hat{\mathbf{E}} = 0$$

if  $\boldsymbol{\epsilon}^T = \boldsymbol{\epsilon}$  and  $\boldsymbol{\mu}^T = \boldsymbol{\mu}$ , the EM operator is symmetric

[Chew et al., *Integral Equation Methods for Electromagnetic and Elastic Waves*, 2008]

$$\mathbb{L}^T = \mathbb{L} \Rightarrow \mathbb{L} \hat{\mathbf{E}} = 0$$

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### **S-parameter Sensitivity Analysis, cont.**

adjoint field can be obtained from the E-field – no need for adjoint system analyses!

how? – set boundary conditions in adjoint problem same as in original problem, incl. those at excitation ports

adjoint field for  $F_{kj}$  turns out to be linearly dependent (in a complex sense) on the original field  $\mathbf{E}_k$

$$\hat{\mathbf{E}}_{kj} = \kappa_{kj} \bar{\mathbf{E}}_k, \quad \kappa_{kj} = -(2V_k j \omega \mu_0)^{-1}$$

exact sensitivity formula for  $S_{kj}$

$$\frac{\partial S_{kj}}{\partial p_n} = \frac{1}{2V_k V_j j \omega \mu_0} \iiint_{\Omega} \bar{\mathbf{E}}_k \cdot \frac{\partial R(\bar{\mathbf{E}}_j)}{\partial p_n} d\Omega$$



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## S-parameter Sensitivity Analysis, cont.

sensitivity formula for shape parameters

$$\frac{\partial S_{kj}}{\partial p_n} = \frac{1}{2V_k V_j j \omega \mu_0} \iiint_{\Omega} \bar{\mathbf{E}}_k \cdot \frac{\Delta_n R(\bar{\mathbf{E}}_j)}{\Delta p_n} d\Omega$$

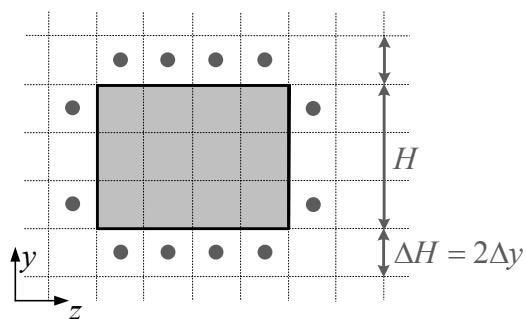
implementation involves assumed perturbations in both forward and backward directions of one cell size

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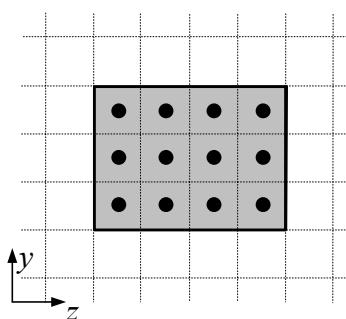
## Memory Requirements: Recording the Field

field is recorded at voxels whose material parameters change as a result of an assumed parameter perturbation

shape parameters



material parameters



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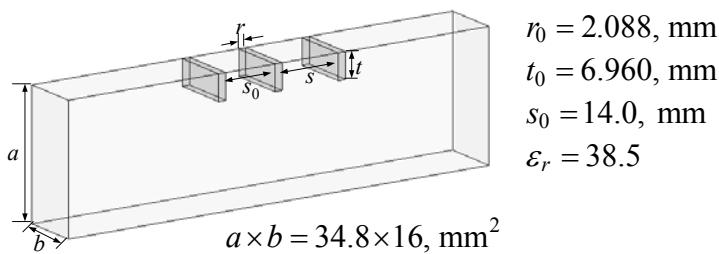
## Algorithm for the Self-adjoint S-parameter Sensitivity Calculation

parameterization: determine optimizable parameters  
generate local FD sensitivity grids at optimizable objects  
calculate derivatives of system coefficients  
acquire E-field solution at sensitivity-grid points at all frequencies  
acquire or calculate modal magnitudes at ports  
calculate sensitivity integral

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## Accuracy of Self-adjoint S-parameter Sensitivities

dielectric-post bandstop filter [Minakova and Rud, 2000]



S-parameter error

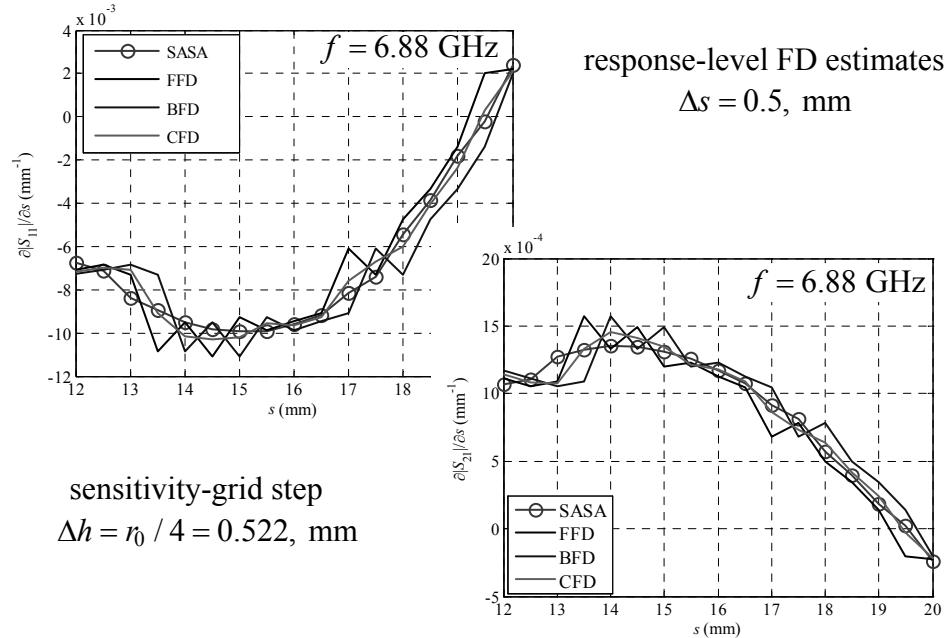
$$e_p = |S_{11}|^2 + |S_{21}|^2 - 1$$

S-parameter derivative error

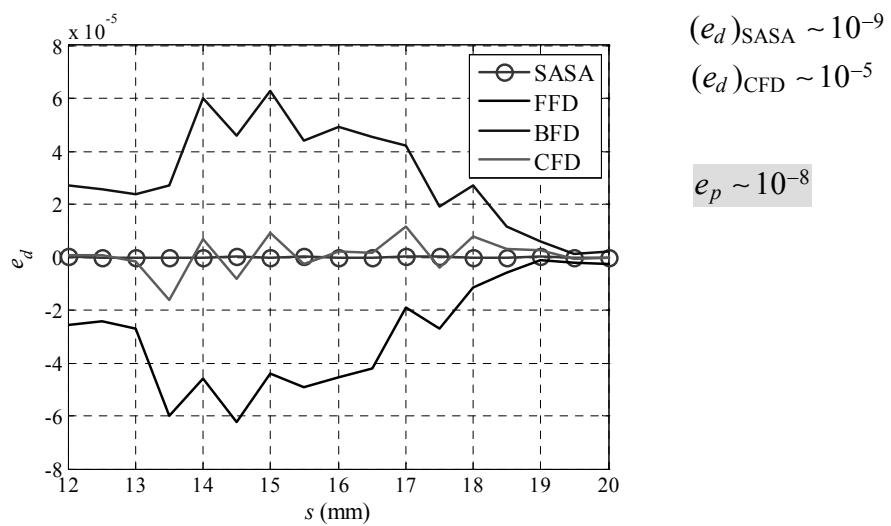
$$e_d = 2|S_{11}| \cdot \frac{\partial |S_{11}|}{\partial p_n} + 2|S_{21}| \cdot \frac{\partial |S_{21}|}{\partial p_n} = 0$$

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### Accuracy of Self-adjoint S-parameter Sensitivities, cont.

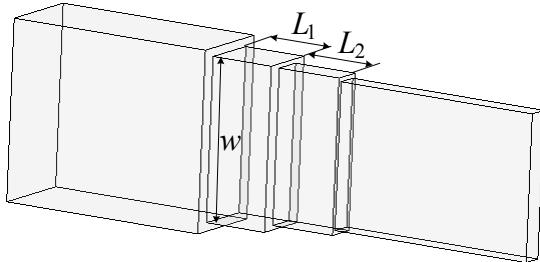


### Accuracy of Self-adjoint S-parameter Sensitivities, cont.



### Accuracy of Self-adjoint S-parameter Sensitivities, cont.

two-section waveguide impedance transformer [Young, 1960]



nominal cross-sections

$$42 \times 21, \text{ mm}^2$$

$$38 \times 14, \text{ mm}^2$$

$$36 \times 7, \text{ mm}^2$$

$$34 \times 5, \text{ mm}^2$$

nominal lengths

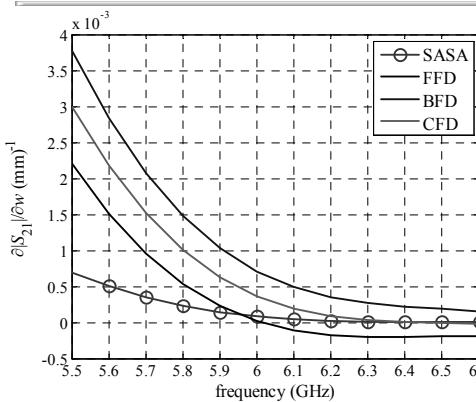
$$L_1 = 15.2, \text{ mm}$$

$$L_2 = 15.6, \text{ mm}$$

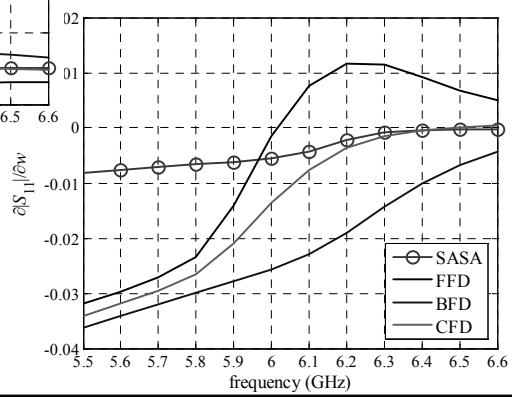
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### Accuracy of Self-adjoint S-parameter Sensitivities, cont.

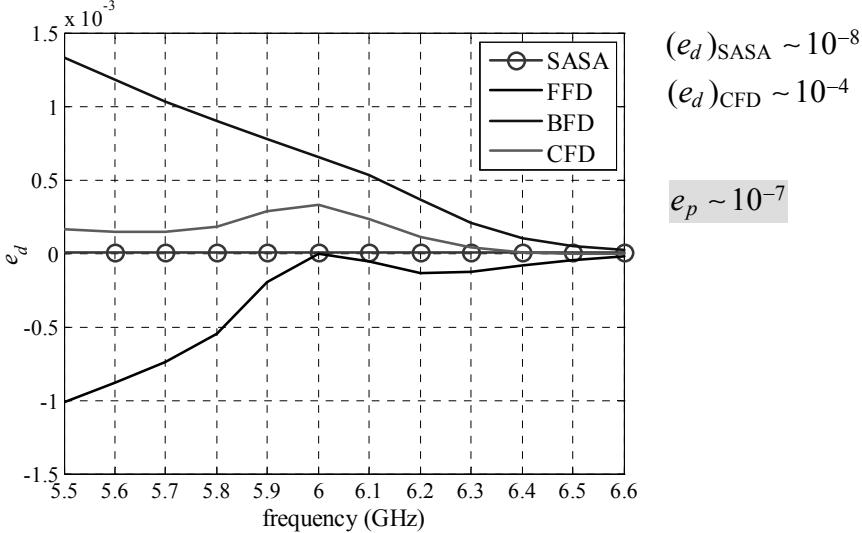
response-level FD estimates  
 $\Delta w = 1.0, \text{ mm}$



sensitivity-grid step  
 $\Delta h = 2.0, \text{ mm}$

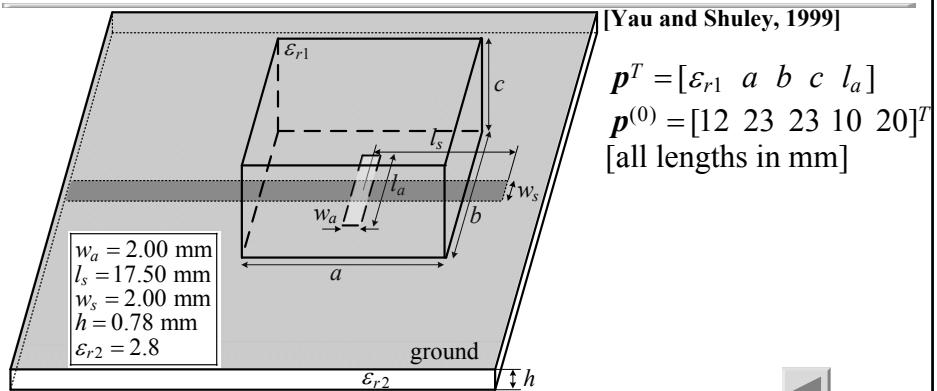


### Accuracy of Self-adjoint S-parameter Sensitivities, cont.



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### Applications in Design Tuning: Dielectric-resonator Antenna



optimization setup (Jacobians: SASA, FFD 4%)

$$\text{optimizer: } \text{minimax } [\text{Bandler, Kellerman, Madsen, 1985}] \quad \Delta_p^{(k)} = \frac{\| \mathbf{p}^{(k+1)} - \mathbf{p}^{(k)} \|}{\| \mathbf{p}^{(k)} \|}$$

initial trust region radius:  $r^{(0)} = 0.01\|\mathbf{p}^{(0)}\|$

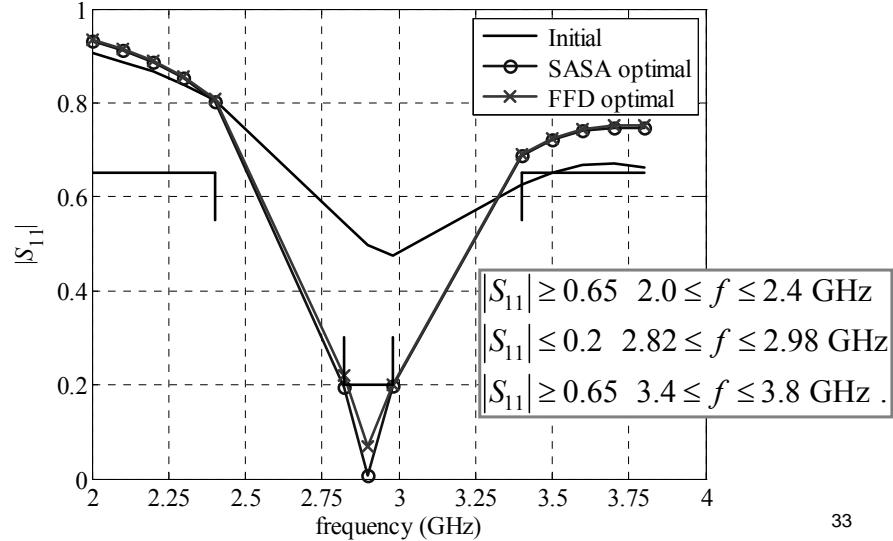
$$\Delta_F^{(k)} = \| F^{(k+1)} - F^{(k)} \|$$

termination criterion:

$$(\Delta_p^{(k)} \leq \delta_p \text{ and } \Delta_p^{(k-1)} \leq \delta_p) \text{ or } (\Delta_F^{(k)} \leq \delta_F \text{ and } \Delta_F^{(k-1)} \leq \delta_F) \quad \delta_p = 0.013 \\ \delta_F = 0.010$$

## Applications in Design Tuning: Dielectric-resonator Antenna, cont.

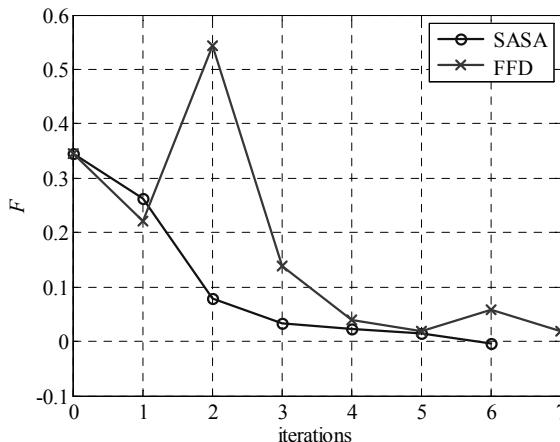
specs, initial design and final designs



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## Applications in Design Tuning: Dielectric-resonator Antenna, cont.

summary of optimization processes



$$\Delta p_{\text{FFD}} = \begin{bmatrix} 0.5 \\ 0.04a \\ 0.04b \\ 0.05c \\ 0.05l_a \end{bmatrix}$$

stops when

SASA opt:  $\Delta_F^{(k)} \leq 0.01$

FFD opt:  $\Delta_p^{(k)} \leq 0.013$

reducing  $\delta_p$  does  
not help FFD opt

$$p_{\text{SASA}}^* = [10.06 \quad 23.66 \quad 23.47 \quad 13.64 \quad 17.46]^T$$

$$p_{\text{FFD}}^* = [10.59 \quad 23.58 \quad 23.21 \quad 12.74 \quad 17.21]^T$$

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## Applications in Design Tuning: Dielectric-resonator Antenna, cont.

CPU time comparison (per optimization iteration)

HFSS frequency sweep: 220 s

SASA Jacobian calculation: 0.1 s

FFD Jacobian calculation: 1100 s

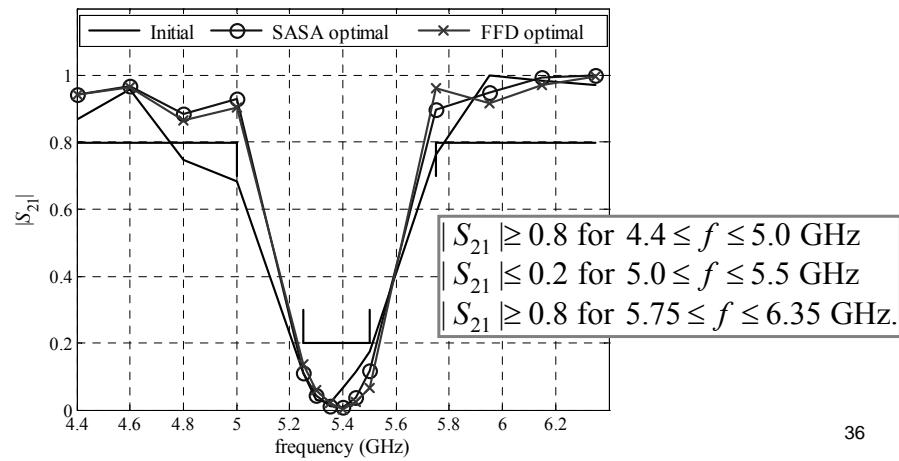
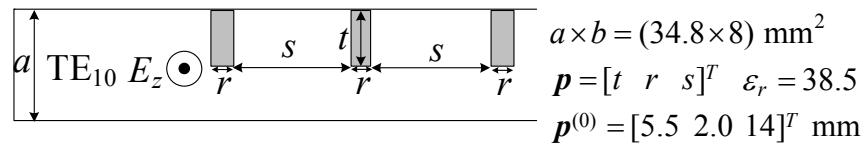
### TOTAL

SASA opt: 1321 s

FFD opt: 9240 s

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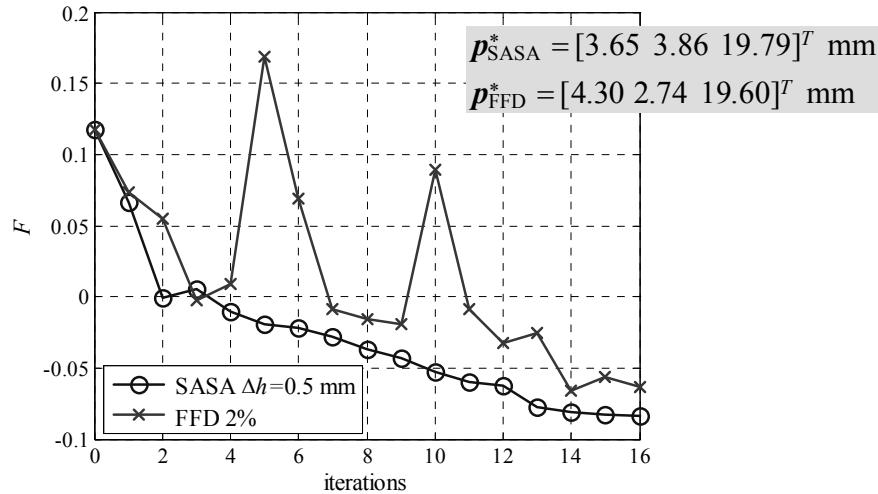
## Applications in Design Tuning: Dielectric-resonator Filter



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## Applications in Design Tuning: Dielectric-resonator Filter, cont.

*minimax* optimization process



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## Applications in Design Tuning: Dielectric-resonator Filter, cont.

CPU time comparison (per optimization iteration)

HFSS frequency sweep: 459 s

SASA Jacobian calculation: 0.45 s

FFD Jacobian calculation: 1377 s

reliability comparison

$$\mathbf{p}^{(0)} = [7.5 \ 1.5 \ 13.5]^T \text{ mm}$$

FFD 2%: does not converge,  $F = 0.2330$

SASA: converges after 20 iterations,  $F = -0.0677$

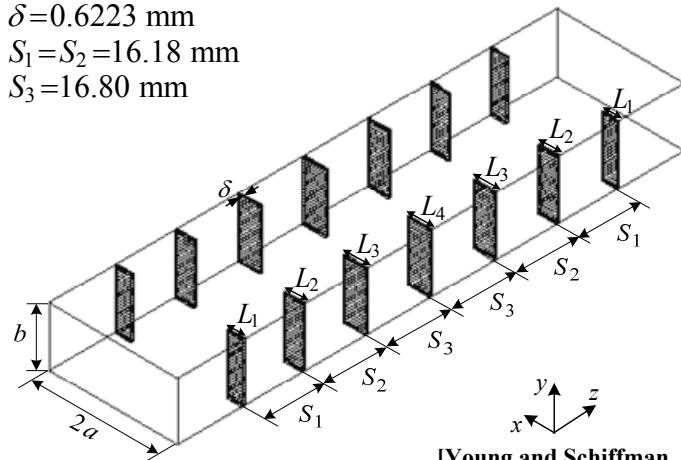
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### Applications in Design Tuning: H-plane Filter

$$\delta = 0.6223 \text{ mm}$$

$$S_1 = S_2 = 16.18 \text{ mm}$$

$$S_3 = 16.80 \text{ mm}$$



[Young and Schiffman, 1963]

values for termination criterion

$$\delta_p = 0.001$$

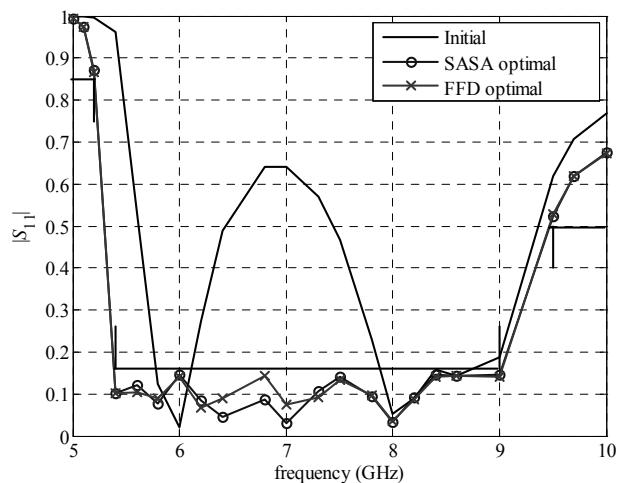
$$\delta_F = 0.009$$

$$\mathbf{p} = [L_1 \ L_2 \ L_3 \ L_4]^T$$

$$\mathbf{p}^{(0)} = [5\delta \ 11\delta \ 9\delta \ 13\delta]^T$$

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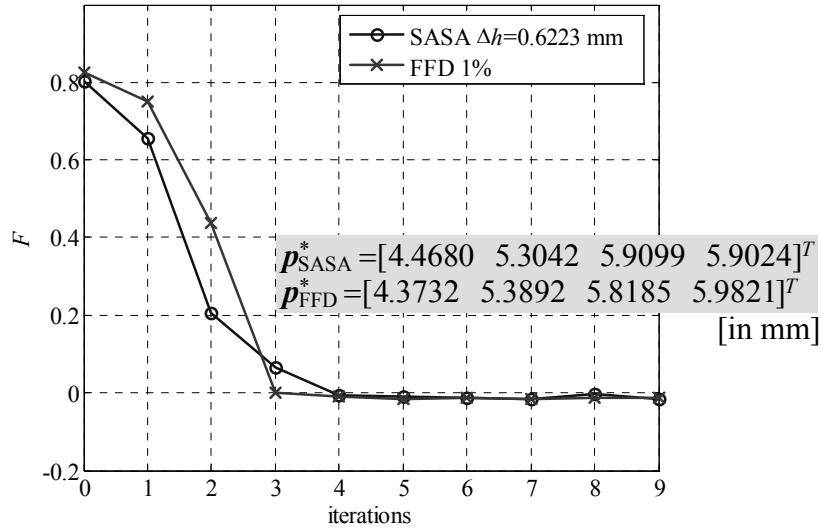
### Applications in Design Tuning: H-plane Filter, cont.



$ S_{11}  \geq 0.85$	$f \leq 5.2 \text{ GHz}$
$ S_{11}  \leq 0.16$	$5.4 \leq f \leq 9 \text{ GHz}$
$ S_{11}  \geq 0.5$	$f \geq 9.5 \text{ GHz}$

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### Applications in Design Tuning: H-plane Filter, cont.



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### Applications in Design Tuning: H-plane Filter, cont.

time comparison

	FFD	SASA
number of iterations	10	10
calls to the simulator	50	10
time for 1 simulation (s)	537	537
Jacobian estimation, total (s)	21 480	1 536 (CPU time $\approx 4$ s)
total optimization time (s)	32 063	7 216

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## Applications in Microwave UWB Imaging

applications of near-field microwave imaging

cancer diagnostics (microwave tomography)

nondestructive testing for structural integrity

concealed weapon detection

etc.

near-field UWB imaging with EM simulations as forward models

medium is complex

exploits near-zone (evanescent) field information

exploits multi-frequency information

exploits co- and cross-polarization scatter

solved as a ***nonlinear optimization problem***

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## Objective Functions in Microwave Imaging, cont.

typical number of optimizable parameters  $N$  is  $10^4$  to  $10^5$   
(permittivity and conductivity of each voxel in the imaged volume)

stochastic optimization approaches are impractical – gradient-based approaches are preferred if Jacobians are available

response-level Jacobian approximations are not possible

adjoint Jacobians do not suffer from accuracy and time limitations  
(may increase memory requirements in time-domain simulations)

minima of 3-D Jacobian maps point directly to possible scatterer locations

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## Objective Function in Microwave Imaging

$$F(\boldsymbol{\varepsilon}, \boldsymbol{\sigma}) = \sum_{i=1}^{N_r} (r_i - \bar{r}_i)^2 + \rho_\varepsilon \sum_{n=1}^N |\varepsilon_n - \varepsilon_{bn}|^2 + \rho_\sigma \sum_{n=1}^N |\sigma_n - \sigma_{bn}|^2$$

*set regularization terms to 0*

$$\boldsymbol{r} \in \mathbb{R}^{N_r \times 1}$$

$$\boldsymbol{\varepsilon}, \boldsymbol{\sigma} \in \mathbb{R}^{N \times 1}$$

two types of responses are derived from  $S$ -parameters

[Li, Trehan and Nikolova, *Inverse Problems*, 2010]

- magnitude response

$$F_M^{(i)}(\tilde{\boldsymbol{\varepsilon}}) = 0.5 \sum_{j,k=1}^K (|S_{kj}^{(i)}| - |\bar{S}_{kj}^{(i)}|)^2 \quad i = 1, \dots, N_f$$

- phase response

$$F_P^{(i)}(\tilde{\boldsymbol{\varepsilon}}) = 0.5 \sum_{j,k=1}^K \left| \exp(j\angle F_{jk}^{(i)}) - \exp(j\angle \bar{F}_{jk}^{(i)}) \right|^2$$

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## Jacobian Maps

Jacobian maps: cost function derivatives plotted vs. voxel location

- magnitude maps

$$\frac{\partial F_M^{(i)}}{\partial p_n} \Bigg|_{p_n=\varepsilon_{r,n}, \sigma_n} = \sum_{j,k=1}^K (|F_{jk}^{(i)}| - |\bar{F}_{jk}^{(i)}|) \frac{\partial |F_{jk}^{(i)}|}{\partial p_n} \quad n = 1, \dots, N \quad i = 1, \dots, N_f$$

where  $\frac{\partial |F|}{\partial p_n} = |F|^{-1} \cdot \left[ \operatorname{Re} F \cdot \operatorname{Re} \left( \frac{\partial F}{\partial p_n} \right) + \operatorname{Im} F \cdot \operatorname{Im} \left( \frac{\partial F}{\partial p_n} \right) \right] \quad F \equiv F_{jk}^{(i)}$

- phase maps

$$\frac{\partial F_P^{(i)}}{\partial p_n} \Bigg|_{p_n=\varepsilon_{r,n}, \sigma_n} = \sum_{j,k=1}^K \sin(\angle F_{jk}^{(i)} - \angle \bar{F}_{jk}^{(i)}) \frac{\partial \angle F_{jk}^{(i)}}{\partial p_n} \quad n = 1, \dots, N \quad i = 1, \dots, N_f$$

where  $\frac{\partial \angle F}{\partial p_n} = |F|^{-2} \cdot \left[ \operatorname{Re} F \cdot \operatorname{Im} \left( \frac{\partial F}{\partial p_n} \right) - \operatorname{Im} F \cdot \operatorname{Re} \left( \frac{\partial F}{\partial p_n} \right) \right]$

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## Jacobian Maps: Summary

- magnitude vs. permittivity maps

$$M_{\epsilon_r}^{(i)}(u, v) = \frac{\partial F_M^{(i)}}{\partial \epsilon_{r,n}} \Big|_{(u,v)}$$

- magnitude vs. conductivity maps

$$M_{\sigma}^{(i)}(u, v) = \frac{\partial F_M^{(i)}}{\partial \sigma_n} \Big|_{(u,v)}$$

- phase vs. permittivity maps

$$P_{\epsilon_r}^{(i)}(u, v) = \frac{\partial F_P^{(i)}}{\partial \epsilon_{r,n}} \Big|_{(u,v)}$$

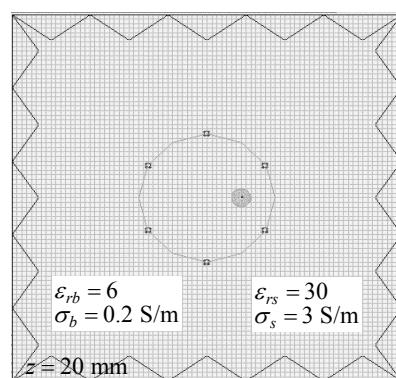
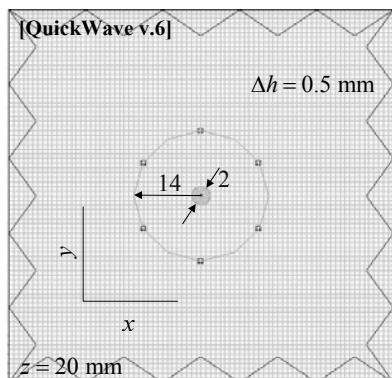
- phase vs. conductivity maps

$$P_{\sigma}^{(i)}(u, v) = \frac{\partial F_P^{(i)}}{\partial \sigma_n} \Big|_{(u,v)}$$

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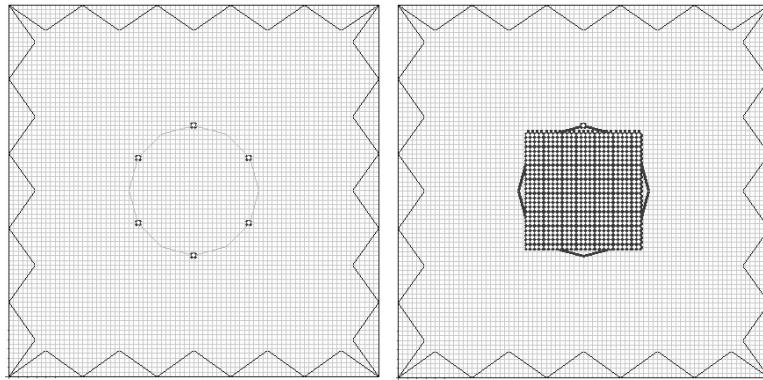
## Example 1: Detecting Scatterer in a Homogeneous Lossy Dielectric

circular array of six probes: vertical polarization only



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### Example 1: Detecting Scatterer in a Homogeneous Lossy Dielectric

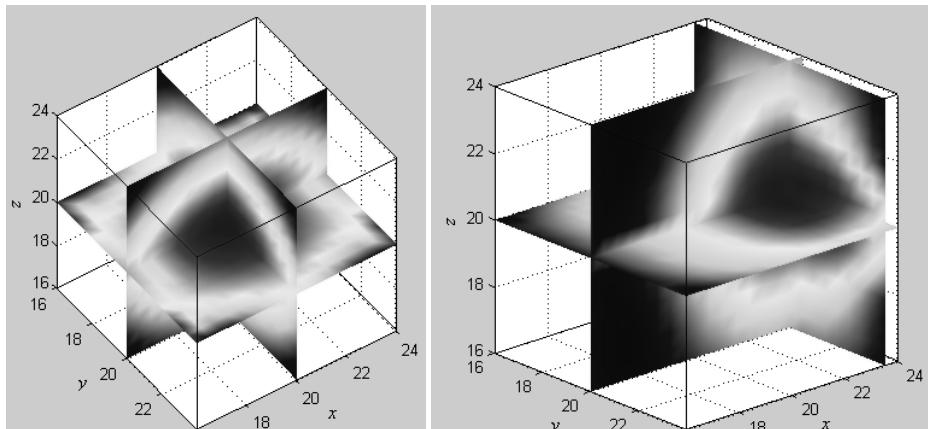


	true center		map minimum	
	$x$	$y$	$x$	$y$
case #1	20.00	20.00	20.00	20.00
case #2	23.50	20.00	23.00	20.00

model structure:  
background only

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### Example 1: Detecting Scatterer in a Homogeneous Lossy Dielectric

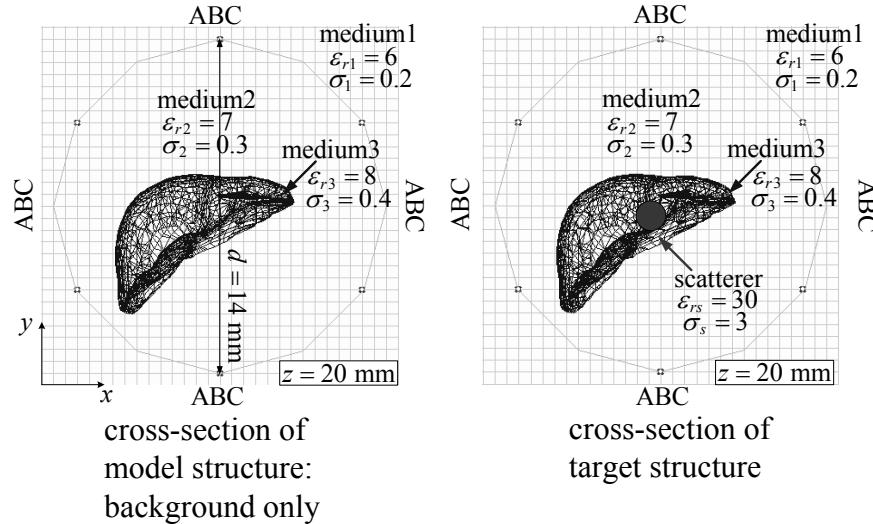


case #1

case #2

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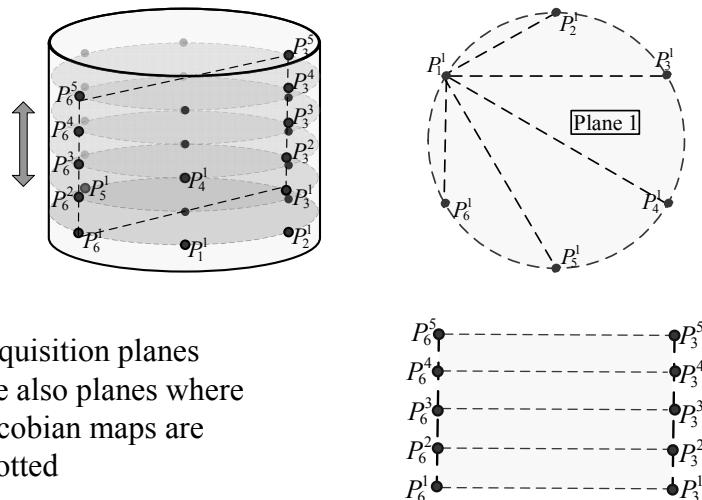
## Example 2: Detecting Scatterer in a Heterogeneous Lossy Dielectric



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### **Example 2: Detecting Scatterer in a Heterogeneous Lossy Dielectric**

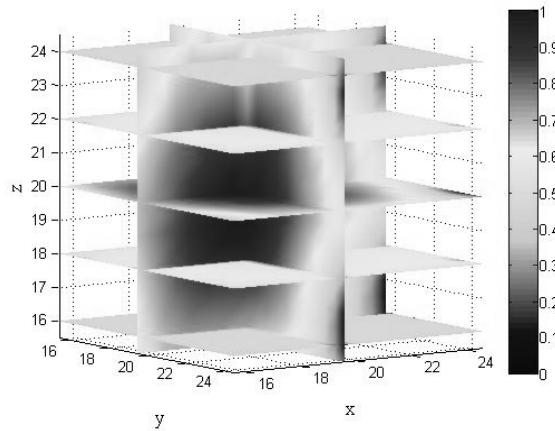
## data acquisition setup for a 3D scan



acquisition planes  
are also planes where  
Jacobian maps are  
plotted

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## Example 2: Detecting Scatterer in a Heterogeneous Lossy Dielectric



Location $(x, y)$ (in mm) in the plane $z = 20$ mm	True Center	Map Minimum
	$(19.00, 19.00)$	$(19.65, 19.73)$

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## Summary

- response sensitivity analysis is crucial in design optimization and the solution of inverse problems
- the AVM is the most efficient method for SA – requires only additional 1 system analysis regardless of the number of parameters
- the self-adjoint method is applicable to network parameters – it does not require any additional system analyses
- numerically efficient – overhead is negligible compared to simulation time regardless of  $N$
- reasonable memory even if  $N$  is on the order of  $10^5$
- versatile: applies to both shape and material parameters

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